

Wide Temperature Range Version 16 M SRAM (1-Mword × 16-bit / 2-Mword × 8-bit)

> REJ03C0195-0102 Rev. 1.02 Feb.23.2017

## **Description**

The R1LV1616HSA-I Series is 16-Mbit static RAM organized 1-Mword × 16-bit / 2-Mword × 8-bit with embedded ECC. R1LV1616HSA-I Series has realized higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). It offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is packaged in 48-pin plastic TSOPI for high density surface mounting.

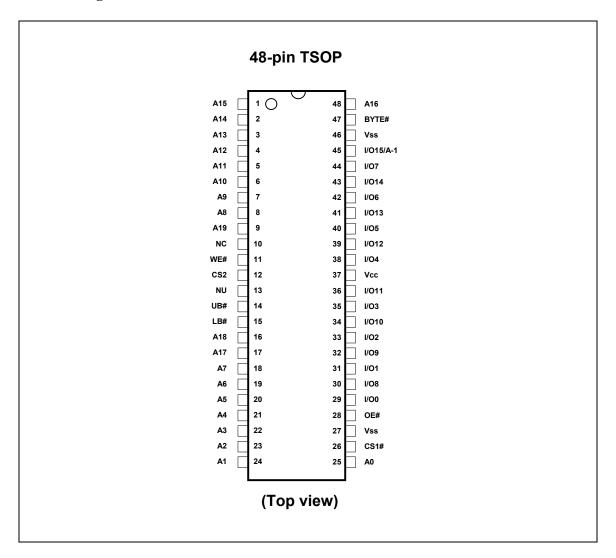
#### **Features**

- Single 3.0 V supply: 2.7 V to 3.6 V
  Fast access time: 45/55 ns (max)
- Power dissipation:
  - Active: 9 mW/MHz (typ)
  - Standby:  $1.5 \mu W \text{ (typ)}$
- Completely static memory.
  - No clock or timing strobe required
- Equal access and cycle times
- Common data input and output.
  - Three state output
- Battery backup operation.
  - 2 chip selection for battery backup
- Temperature range: -40 to +85°C
- Byte function (x8 mode) available by BYTE# & A-1
- Embedded ECC (error checking and correction) for single-bit error correction

# **Ordering Information**

Type No.	Access time	Package
R1LV1616HSA-4SI	45 ns	48-pin plastic TSOPI
R1LV1616HSA-5SI	55 ns	

## Pin Arrangement

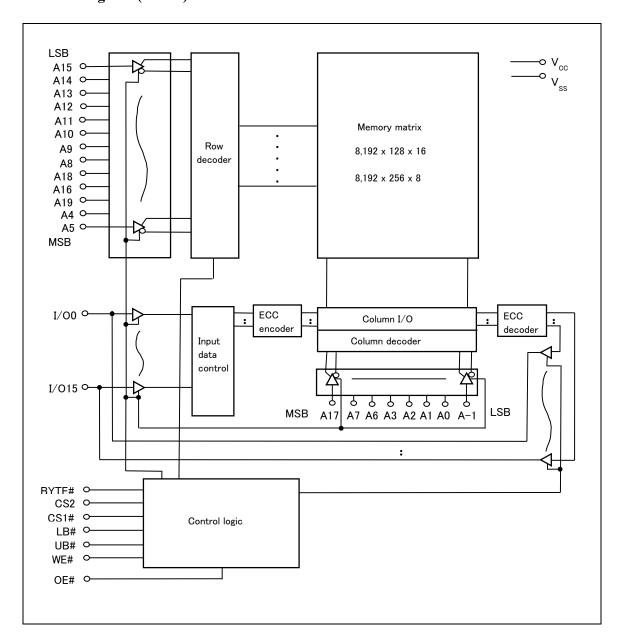


# **Pin Description** (TSOP)

Pin name	Function
A0 to A19	Address input (word mode)
A-1 to A19	Address input (byte mode)
I/O0 to I/O15	Data input/output
CS1# (CSI)	Chip select 1
CS2	Chip select 2
WE# (WE)	Write enable
OE# (OE)	Output enable
LB# (LB)	Lower byte select
$\overline{UB}$ $\overline{UB}$ $\overline{UB}$ $\overline{UB}$	Upper byte select
BYTE# (BYTE)	Byte enable
Vcc	Power supply
V <sub>SS</sub>	Ground
NC	No connection
NU*1	Not used (test mode pin)

Note: 1. This pin should be connected to a ground (Vss), or not be connected (open).

#### **Block Diagram (TSOP)**



# $\textbf{Operation Table} \ (TSOP)$

## Byte mode

CS1#	CS2	WE#	OE#	UB#	LB#	BYTE#	I/O0 to I/O7	I/O8 to I/O14	I/O15	Operation
Н	×	×	×	×	×	L	High-Z	High-Z	High-Z	Standby
×	L	×	×	×	×	L	High-Z	High-Z	High-Z	Standby
L	Н	Н	L	×	×	L	Dout	High-Z	A-1	Read
L	Н	L	×	×	×	L	Din	High-Z	A-1	Write
L	Н	Н	Н	×	×	L	High-Z	High-Z	High-Z	Output disable

Note: H: V<sub>IH</sub>, L: V<sub>IL</sub>, ×: V<sub>IH</sub> or V<sub>IL</sub>

#### Word mode

CS1#	CS2	WE#	OE#	UB#	LB#	BYTE#	I/O0 to I/O7	I/O8 to I/O14	I/O15	Operation
Н	×	×	×	×	×	Н	High-Z	High-Z	High-Z	Standby
×	L	×	×	×	×	Н	High-Z	High-Z	High-Z	Standby
×	×	×	×	Н	Н	Н	High-Z	High-Z	High-Z	Standby
L	Н	Н	L	L	L	Н	Dout Dout		Dout	Read
L	Н	Н	L	Н	L	Н	Dout	High-Z	High-Z	Lower byte read
L	Н	Н	L	L	Н	Н	High-Z	Dout	Dout	Upper byte read
L	Н	L	×	L	L	Н	Din	Din	Din	Write
L	Н	L	×	Н	L	Н	Din	High-Z	High-Z	Lower byte write
L	Н	L	×	L	Н	Н	High-Z	Din	Din	Upper byte write
L	Н	Н	Н	×	×	Н	High-Z	High-Z	High-Z	Output disable

Note: H: V<sub>IH</sub>, L: V<sub>IL</sub>, ×: V<sub>IH</sub> or V<sub>IL</sub>

# **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Power supply voltage relative to Vss	Vcc	-0.5 to +4.6	V
Terminal voltage on any pin relative to Vss	V <sub>T</sub>	$-0.5^{*1}$ to V <sub>CC</sub> + $0.3^{*2}$	V
Power dissipation	PT	1.0	W
Storage temperature range	Tstg	-55 to +125	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Notes: 1.  $V_T$  min: -2.0 V for pulse half-width  $\leq 10$  ns.

2. Maximum voltage is +4.6 V.

# **DC Operating Conditions**

Parameter	Symbol	Min	Тур	Max	Unit	Note
Supply voltage	Vcc	2.7	3.0	3.6	V	
	Vss	0	0	0	V	
Input high voltage	V <sub>IH</sub>	2.2		V <sub>CC</sub> + 0.3	V	
Input low voltage	VIL	-0.3	_	0.6	V	1
Ambient temperature range	Та	-40		+85	°C	

Note: 1.  $V_{IL}$  min: -2.0 V for pulse half-width  $\leq 10$  ns.

## **DC** Characteristics

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions*2
Input leakage current	lu	_	_	1	μА	Vin = Vss to Vcc
Output leakage current	lL0	_		1	μΑ	CS1# = $V_{IH}$ or CS2 = $V_{IL}$ or OE# = $V_{IH}$ or WE# = $V_{IL}$ or LB# = UB# = $V_{IH}$ , $V_{I/O}$ = $V_{SS}$ to $V_{CC}$
Operating current	Icc	_	_	20	mA	CS1# = V <sub>IL</sub> , CS2 = V <sub>IH</sub> , Others = V <sub>IH</sub> / V <sub>IL</sub> , I <sub>I/O</sub> = 0 mA
Average operating current	I <sub>CC1</sub> (READ)	_	22*1	35	mA	$\begin{aligned} &\text{Min. cycle, duty} = 100\%, \\ &I_{I/O} = 0 \text{ mA, CS1\#} = V_{IL}, \text{CS2} = V_{IH}, \\ &\text{WE\#} = V_{IH}, \text{Others} = V_{IH}/V_{IL} \end{aligned}$
	Icc1	_	30*1	50	mA	Min. cycle, duty = 100%, $I_{I/O}$ = 0 mA, CS1# = $V_{IL}$ , CS2 = $V_{IH}$ , Others = $V_{IH}/V_{IL}$
	I <sub>CC2</sub> *3 (READ)	_	3*1	8	mA	Cycle time = 70 ns, duty = 100%, $I_{I/O}$ = 0 mA, CS1# = $V_{IL}$ , CS2 = $V_{IH}$ , WE# = $V_{IH}$ , Others = $V_{IH}/V_{IL}$ Address increment scan or decrement scan
	Icc2*3	_	20*1	30	mA	Cycle time = 70 ns, duty = 100%, $I_{I/O}$ = 0 mA, CS1# = $V_{IL}$ , CS2 = $V_{IH}$ , Others = $V_{IH}/V_{IL}$ Address increment scan or decrement scan
	Іссз		3*1	8	mA	$\begin{split} &\text{Cycle time} = 1 \; \mu\text{s, duty} = 100\%, \\ &\text{I}_{\text{I/O}} = 0 \; \text{mA, CS1\#} \leq 0.2 \; \text{V,} \\ &\text{CS2} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V} \\ &\text{V}_{\text{IH}} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V, V}_{\text{IL}} \leq 0.2 \; \text{V} \end{split}$
Standby current	I <sub>SB</sub>	_	0.1*1	0.5	mA	CS2 = V <sub>IL</sub>
Standby current	ISB1	_	0.5*1	8	μΑ	$ \begin{array}{l} 0 \; V \leq Vin \\ (1) \; 0 \; V \leq CS2 \leq 0.2 \; V \; or \\ (2) \; CS1\# \geq V_{CC} - 0.2 \; V, \\ CS2 \geq V_{CC} - 0.2 \; V \; or \\ (3) \; LB\# = UB\# \geq V_{CC} - 0.2 \; V, \\ CS2 \geq V_{CC} - 0.2 \; V, \\ CS1\# \leq 0.2 \; V \\ Average \; value \\ \end{array} $
Output high voltage	Voн	2.4			V	I <sub>OH</sub> = -1 mA
	Vон	V <sub>CC</sub> - 0.2	_	_	V	$I_{OH} = -100 \mu A$
Output low voltage	VoL	_		0.4	V	I <sub>OL</sub> = 2 mA
	VoL	_	_	0.2	V	I <sub>OL</sub> = 100 μA

Notes: 1. Typical values are at  $V_{CC}$  = 3.0 V, Ta = +25°C and not guaranteed.

2. BYTE#  $\geq V_{CC} - 0.2 \ V$  or BYTE#  $\leq 0.2 \ V$ 

3. I<sub>CC2</sub> is the value measured while the valid address is increasing or decreasing by one bit.

Word mode: LSB (least significant bit) is A0. Byte mode: LSB (least significant bit) is A-1.

## Capacitance

 $(Ta = +25^{\circ}C, f = 1.0 \text{ MHz})$ 

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions	Note
Input capacitance	Cin	_		8	pF	Vin = 0 V	1
Input/output capacitance	C <sub>I/O</sub>	_		10	pF	V <sub>I/O</sub> = 0 V	1

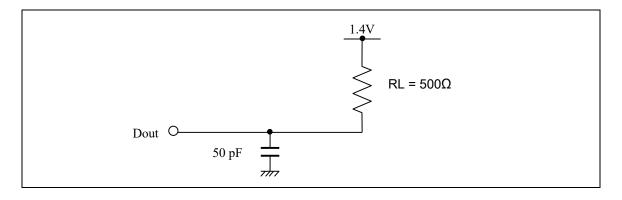
Note: 1. This parameter is sampled and not 100% tested.

#### **AC Characteristics**

(Ta = -40 to +85°C,  $V_{CC}$  = 2.7 V to 3.6 V, unless otherwise noted.)

#### **Test Conditions**

- Input pulse levels:  $V_{IL} = 0.4 \text{ V}$ ,  $V_{IH} = 2.4 \text{ V}$
- Input rise and fall time: 5 ns
- Input and output timing reference levels: 1.4 V
- Output load: See figures (Including scope and jig)



## Read Cycle

		R1LV1616HSA-I					
		-4	-4SI		SI		
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t <sub>RC</sub>	45	_	55	_	ns	
Address access time	t <sub>AA</sub>	_	45	_	55	ns	
Chip select access time	t <sub>ACS1</sub>	_	45	_	55	ns	
	t <sub>ACS2</sub>	_	45	_	55	ns	
Output enable to output valid	toe	_	30	_	35	ns	
Output hold from address change	tон	10		10	_	ns	
LB#, UB# access time	t <sub>BA</sub>	_	45	_	55	ns	
Chip select to output in low-Z	t <sub>CLZ1</sub>	10		10	_	ns	2, 3
	t <sub>CLZ2</sub>	10		10	_	ns	2, 3
LB#, UB# enable to low-Z	t <sub>BLZ</sub>	5		5	_	ns	2, 3
Output enable to output in low-Z	tolz	5		5	_	ns	2, 3
Chip deselect to output in high-Z	t <sub>CHZ1</sub>	0	20	0	20	ns	1, 2, 3
	t <sub>CHZ2</sub>	0	20	0	20	ns	1, 2, 3
LB#, UB# disable to high-Z	t <sub>BHZ</sub>	0	15	0	20	ns	1, 2, 3
Output disable to output in high-Z	tonz	0	15	0	20	ns	1, 2, 3

# Write Cycle

		R1LV1616HSA-I					
		-4	·SI	-5	SI		
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	twc	45		55	_	ns	
Address valid to end of write	t <sub>AW</sub>	45		50	_	ns	
Chip selection to end of write	t <sub>CW</sub>	45		50	_	ns	5
Write pulse width	t <sub>WP</sub>	35		40	_	ns	4
LB#, UB# valid to end of write	t <sub>BW</sub>	45		50		ns	
Address setup time	tas	0		0	_	ns	6
Write recovery time	twR	0		0	_	ns	7
Data to write time overlap	t <sub>DW</sub>	25		25	_	ns	
Data hold from write time	t <sub>DH</sub>	0		0	_	ns	
Output active from end of write	tow	5		5		ns	2
Output disable to output in high-Z	tonz	0	15	0	20	ns	1, 2
Write to output in high-Z	twnz	0	15	0	20	ns	1, 2

#### **Byte Control**

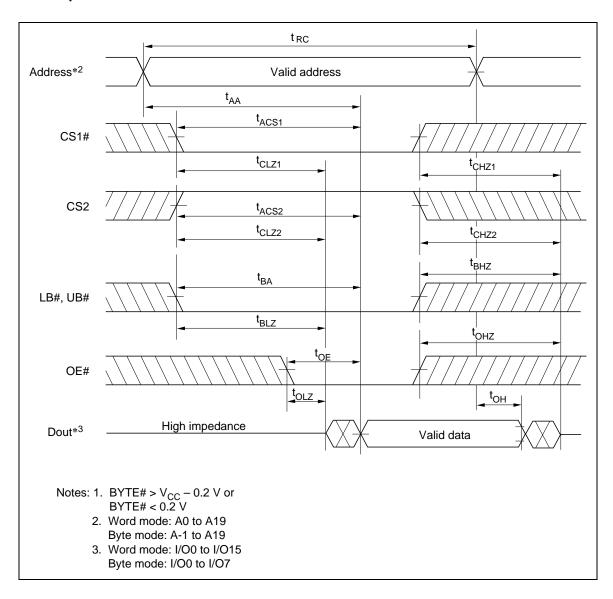
			R1LV1616HSA-I				
		-4SI		-5SI			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
BYTE# setup time	t <sub>BS</sub>	5		5	_	ms	
BYTE# recovery time	t <sub>BR</sub>	5		5	_	ms	

Notes: 1. t<sub>CHZ</sub>, t<sub>OHZ</sub>, t<sub>WHZ</sub> and t<sub>BHZ</sub> are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

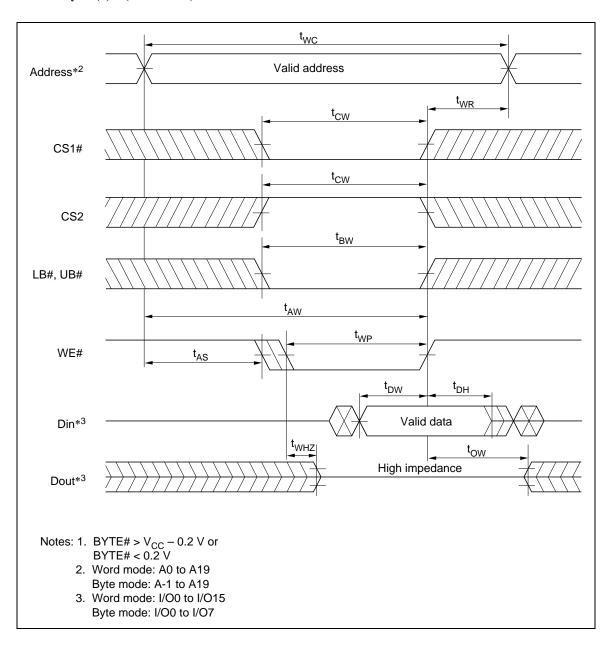
- 2. This parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition,  $t_{HZ}$  max is less than  $t_{LZ}$  min both for a given device and from device to device.
- 4. A write occurs during the overlap of a low CS1#, a high CS2, a low WE# and a low LB# or a low UB#. A write begins at the latest transition among CS1# going low, CS2 going high, WE# going low and LB# going low or UB# going low. A write ends at the earliest transition among CS1# going high, CS2 going low, WE# going high and LB# going high or UB# going high. twp is measured from the beginning of write to the end of write.
- 5. t<sub>CW</sub> is measured from the later of CS1# going low or CS2 going high to the end of write.
- 6. tas is measured from the address valid to the beginning of write.
- 7. twR is measured from the earliest of CS1# or WE# going high or CS2 going low to the end of write cycle.

# **Timing Waveform**

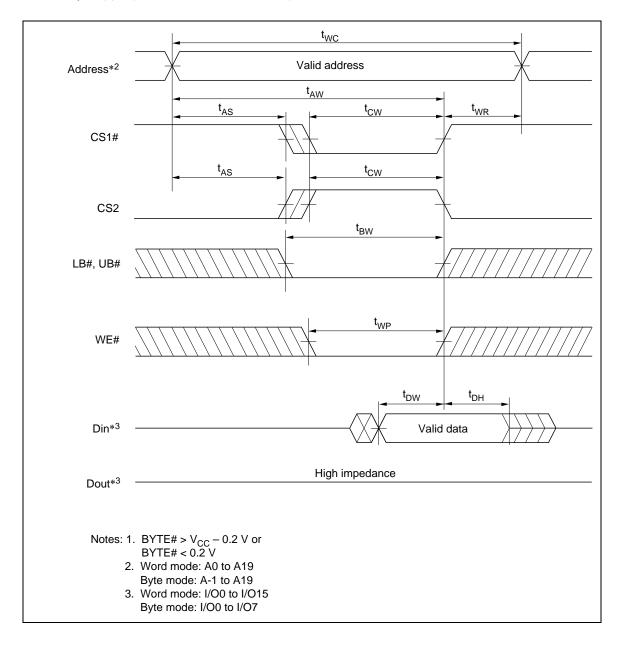
## Read Cycle\*1



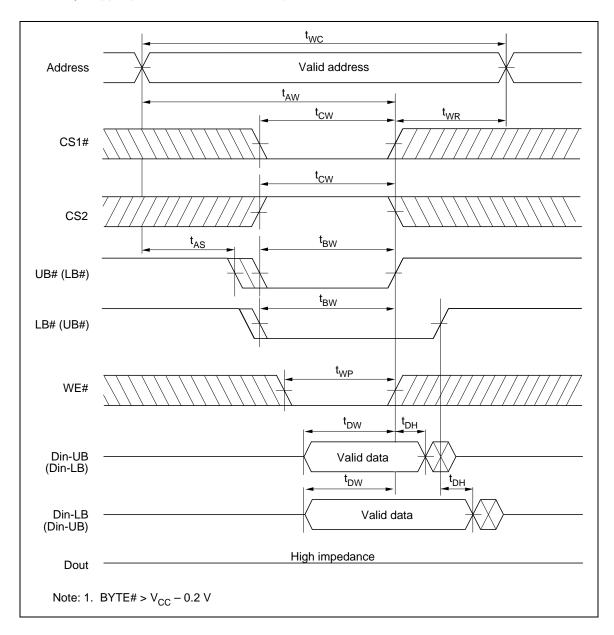
#### Write Cycle (1)\*1 (WE# Clock)



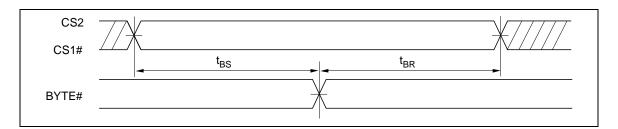
Write Cycle (2)\*1 (CS1#, CS2 Clock, OE# =  $V_{IH}$ )



Write Cycle (3)\* $^{1}$  (LB#, UB# Clock, OE# =  $V_{IH}$ )



## Byte Control (TSOP)



## Low $V_{CC}$ Data Retention Characteristics

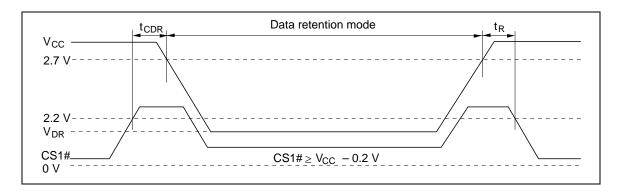
 $(Ta = -40 \text{ to } +85^{\circ}C)$ 

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions*2,3
V <sub>CC</sub> for data retention	$V_{DR}$	1.5	_	3.6	V	$\begin{split} & \text{Vin} \geq 0 \text{ V} \\ & \text{(1)} \ 0 \ \text{V} \leq \text{CS2} \leq 0.2 \ \text{V} \text{ or} \\ & \text{(2)} \ \text{CS2} \geq \text{V}_{\text{CC}} - 0.2 \ \text{V}, \\ & \text{CS1\#} \geq \text{V}_{\text{CC}} - 0.2 \ \text{V} \text{ or} \\ & \text{(3)} \ \text{LB\#} = \text{UB\#} \geq \text{V}_{\text{CC}} - 0.2 \ \text{V}, \\ & \text{CS2} \geq \text{V}_{\text{CC}} - 0.2 \ \text{V}, \\ & \text{CS1\#} \leq 0.2 \ \text{V} \end{split}$
Data retention current	ICCDR	_	0.5*1	∞	μА	$\begin{split} &V_{CC} = 3.0 \text{ V}, \text{ Vin } \geq 0 \text{ V} \\ &(1) \text{ 0 V} \leq \text{CS2} \leq 0.2 \text{ V or} \\ &(2) \text{ CS2} \geq V_{CC} - 0.2 \text{ V}, \\ &\text{ CS1\#} \geq V_{CC} - 0.2 \text{ V or} \\ &(3) \text{ LB\#} = \text{UB\#} \geq V_{CC} - 0.2 \text{ V}, \\ &\text{ CS2} \geq V_{CC} - 0.2 \text{ V}, \\ &\text{ CS1\#} \leq 0.2 \text{ V} \\ &\text{Average value} \end{split}$
Chip deselect to data retention time	t <sub>CDR</sub>	0		_	ns	See retention waveforms
Operation recovery time	t <sub>R</sub>	5	_		ms	

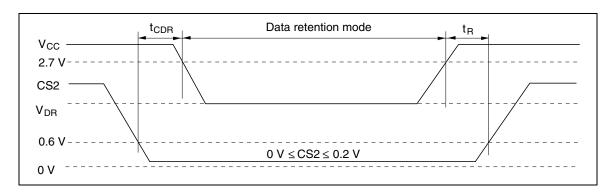
Notes: 1. Typical values are at  $V_{CC} = 3.0 \text{ V}$ ,  $Ta = +25^{\circ}\text{C}$  and not guaranteed.

- 2. BYTE#  $\geq$  V<sub>CC</sub> 0.2 V or BYTE#  $\leq$  0.2 V
- 3. CS2 controls address buffer, WE# buffer, CS1# buffer, OE# buffer, LB#, UB# buffer and Din buffer. If CS2 controls data retention mode, Vin levels (address, WE#, OE#, CS1#, LB#, UB#, I/O) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be  $CS2 \geq V_{CC} 0.2 \ V \text{ or } 0 \ V \leq CS2 \leq 0.2 \ V.$  The other input levels (address, WE#, OE#, LB#, UB#, I/O) can be in the high impedance state.

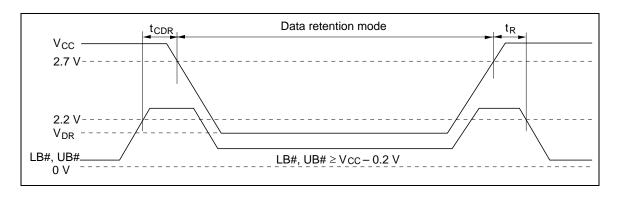
#### Low $V_{CC}$ Data Retention Timing Waveform (1) (CS1# Controlled)



#### Low $V_{CC}$ Data Retention Timing Waveform (2) (CS2 Controlled)



Low Vcc Data Retention Timing Waveform (3) (LB#, UB# Controlled)



# Revision History

## R1LV1616HSA-I Series Data Sheet

Rev.	Date	Contents of Modification	
		Page	Description
1.00	Apr.22.2004	_	Initial issue
1.01	Nov.18.2004	_	Addition of 2-Mword x 8-bit function
1.02	Feb.23.2017	p.1,p.5	Disclosed embedded ECC features
		p.2	Deleted previous package code (48P3R-B)

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